

HIGH-SPEED CABLES FOR PCIe 5.0 / 6.0 AND IEEE802.3ck: SIGNAL INTEGRITY CHALLENGES, PERFORMANCE PARAMETERS AND TEST AUTOMATION

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ROHDE & SCHWARZ

Make ideas real

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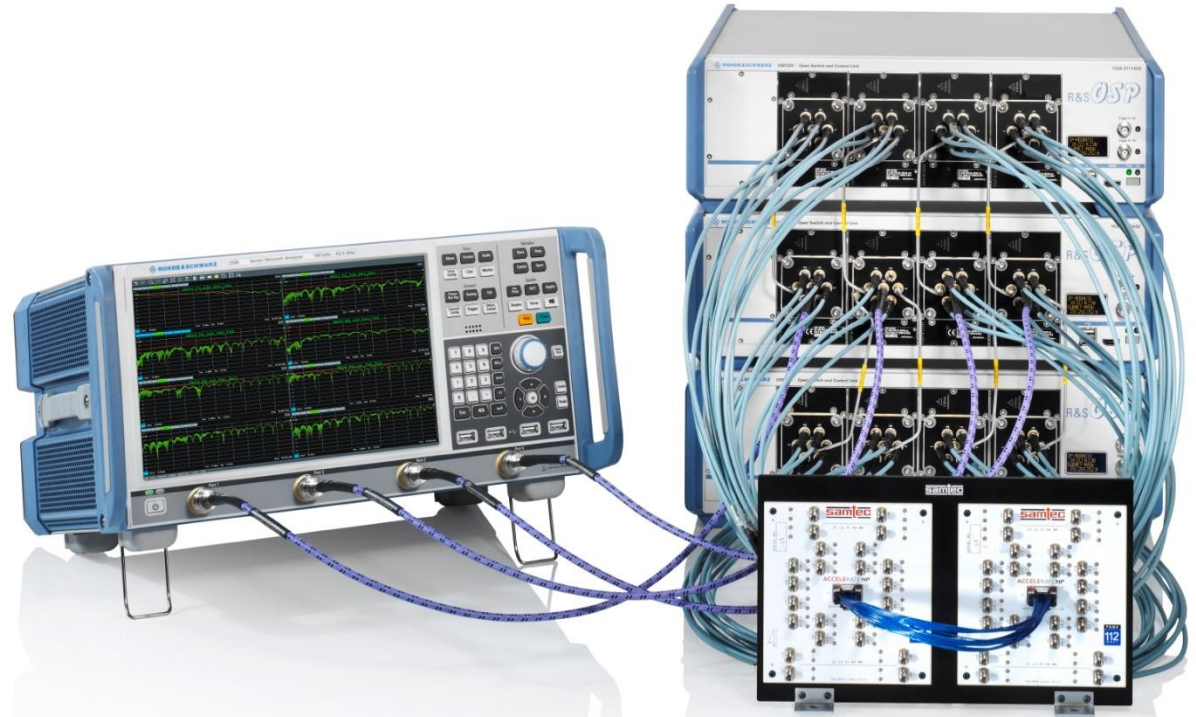
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HIGH-SPEED CABLES FOR PCIe 5.0 / 6.0 AND IEEE802.3ck

SIGNAL INTEGRITY CHALLENGES, PERFORMANCE PARAMETERS AND TEST ASPECTS



DATA CENTER ECOSYSTEM: EVOLUTION OF KEY TECHNOLOGIES

PCIe: Processing, Storage

PCIe Spec.	Raw BW (per lane)	Modulation NRZ / PAM	Symbol Rate (per lane)
...			
PCIe 4.0: for 16.0 GT/s	16.0 Gbps	NRZ	16.0 GBd
PCIe 5.0 for 32.0 GT/s	32.0 Gbps	NRZ	32.0 GBd
PCIe 6.0 for 64 GT/s	64.0 Gbps	PAM4	32.0 GBd
PCIe 7.0 for 128 GT/s

IEEE 802.3: Datacom

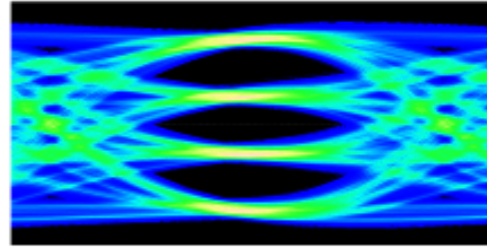
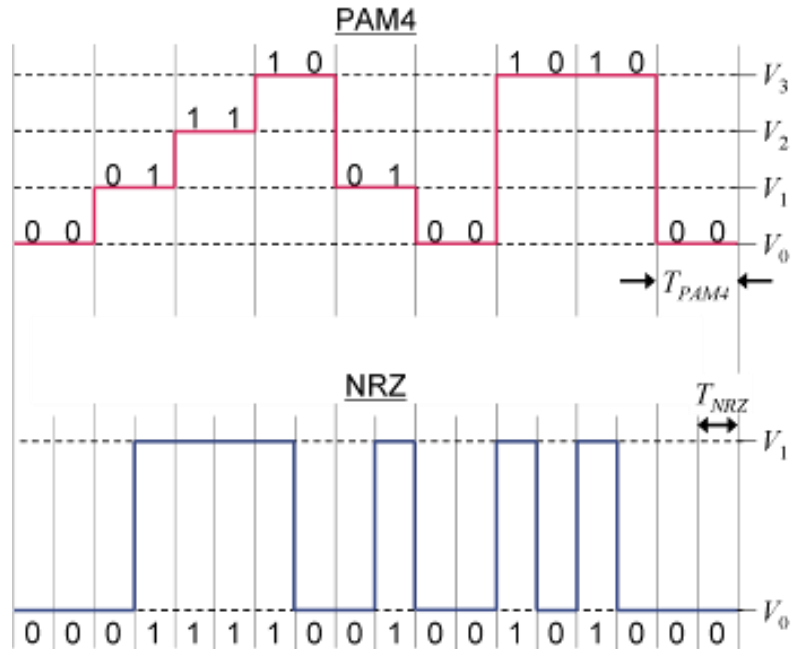
IEEE Spec.	Raw BW (per lane)	Modulation NRZ / PAM	Symbol Rate (per lane)
...	...		
802.3bj/by	25.78125 Gb/s	NRZ	25.78125 GBd
802.3cd	53.125 Gb/s	PAM4	26.5625 GBd
802.3ck	106.25 Gb/s	PAM4	53.125 GBd
802.3dj

used cable formats: x1, x2, x4, x8, x16

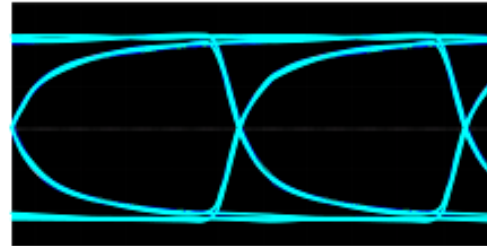
used cable formats: CR1, CR2, CR4, CR8, CR16



GENERAL SIGNAL INTEGRITY CHALLENGES: CROSSTALK IN SYSTEMS WITH PAM 4



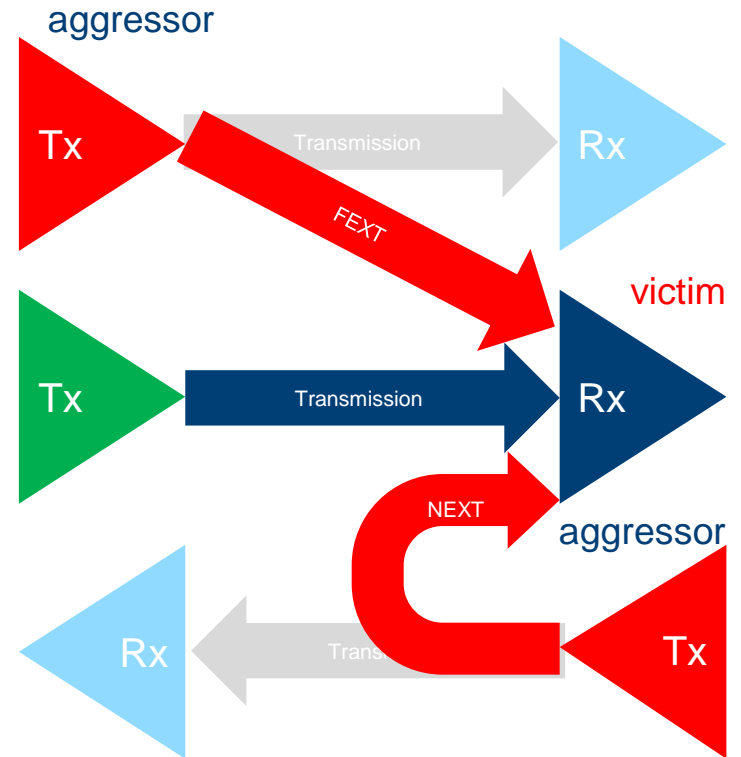
$$BW_{PAM4} = \frac{1}{2} BW_{NRZ}$$



eye height for PAM4 is 1/3 of eye height for NRZ: $20 \log (1/3) = -9.5 \text{ dB}$
→ higher sensitivity to noise and crosstalk

GENERAL SIGNAL INTEGRITY CHALLENGES: CROSSTALK

- ▶ crosstalk:
 - near end crosstalk: NEXT
 - far end crosstalk: FEXT
- ▶ multiple aggressors: power sum
 - power sum NEXT: PSNEXT or multi-disturber NEXT: MDNEXT
 - power sum FEXT: PSFEXT or multi-disturber FEXT: MDFEXT



TEST PARAMETERS IN PCIe 5.0 / 6.0

EXAMPLE: PCIe 5.0 / 6.0 INTERNAL AND EXTERNAL CABLES

Parameters according to PCIe Specification:

- ▶ Differential Insertion Loss (Sdd21): mask check against IL limit mask
- ▶ Differential Return Loss (Sdd11 and Sdd22): mask check against RL limit mask
iRL metric: method of waiver, if RL violates limit mask
- ▶ NEXT and PSNEXT (power sum of individual NEXT aggressors): mask check against PSNEXT limit mask
cclCN_{NEXT} metric: method of waiver, if PSNEXT violates limit mask
- ▶ FEXT and PSFEXT (power sum of individual FEXT aggressors): mask check against PSFEXT limit mask
cclCN_{FEXT} metric: method of waiver, if PSFEXT violates limit mask
- ▶ Intra-Pair Skew EIPS (Effective Intra-Pair Skew): limit check
- ▶ Inter-Pair Skew (Lane-to-Lane Skew): limit check

Beyond Specification:

- ▶ Differential Trace Impedance Profile
- ▶ ...

TEST PARAMETERS IN IEEE 802.3ck

EXAMPLE: 802.3ck COPPER CABLE ASSEMBLIES (CR)

Parameters according to IEEE Specification:

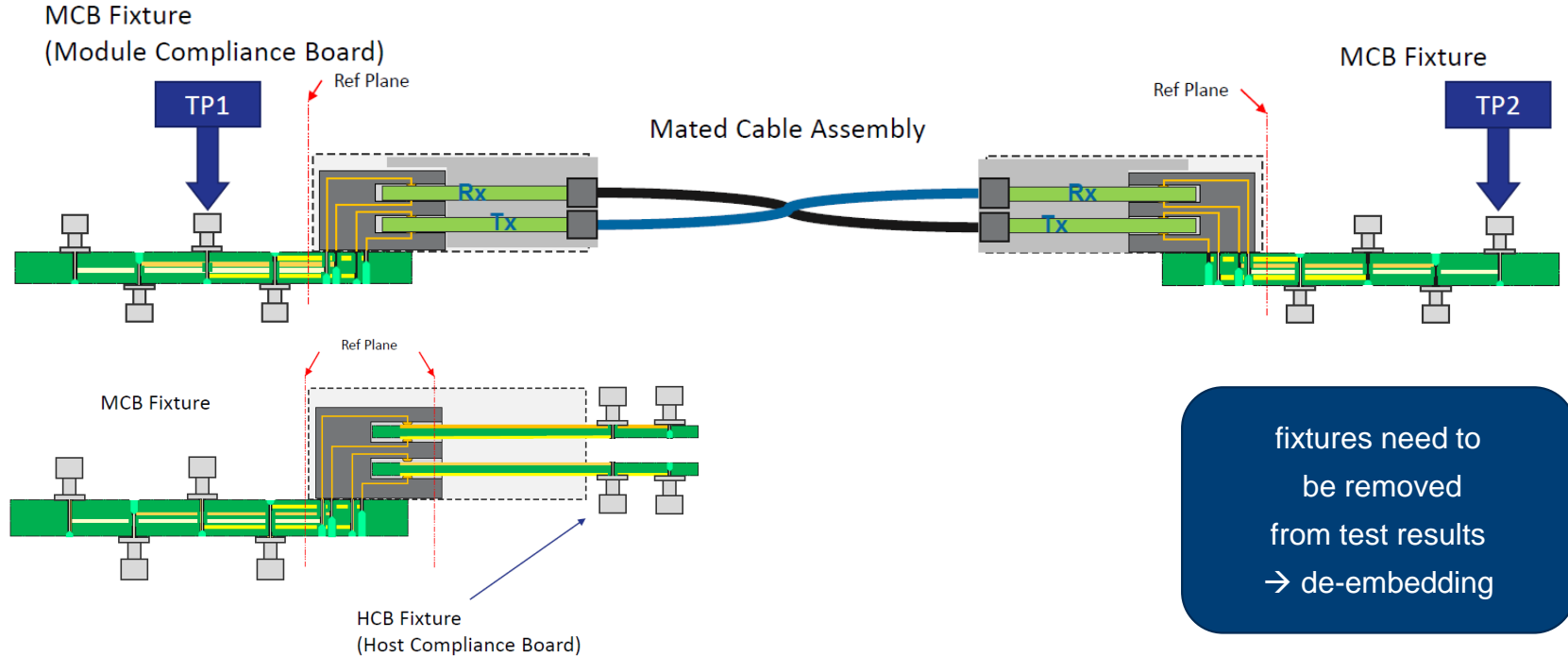
- ▶ Differential Insertion Loss (Sdd21): mask check against ILdd limit mask
- ▶ Differential-Mode to Common-Mode Return Loss (Scd11 and Scd22): mask check against RLcd limit mask
- ▶ Differential-Mode to Common-Mode Insertion Loss (Scd21) minus Differential Insertion Loss (Sdd21): mask check against ILcd-ILdd limit mask
- ▶ Common-Mode to Common-Mode Return Loss (Scc11 and Scc22): mask check against RLcc limit mask
- ▶ Metrics:
 - Channel Operating Margin (COM)
 - for cable assemblies with $COM < 4\text{dB}$:
Effective Return Loss (ERL)

Beyond Specification:

- ▶ Differential Trace Impedance Profile
- ▶ ...

REFERENCE PLANE DEFINITION IN PCIe

EXAMPLE: PCIe 5.0 / 6.0 INTERNAL AND EXTERNAL CABLES



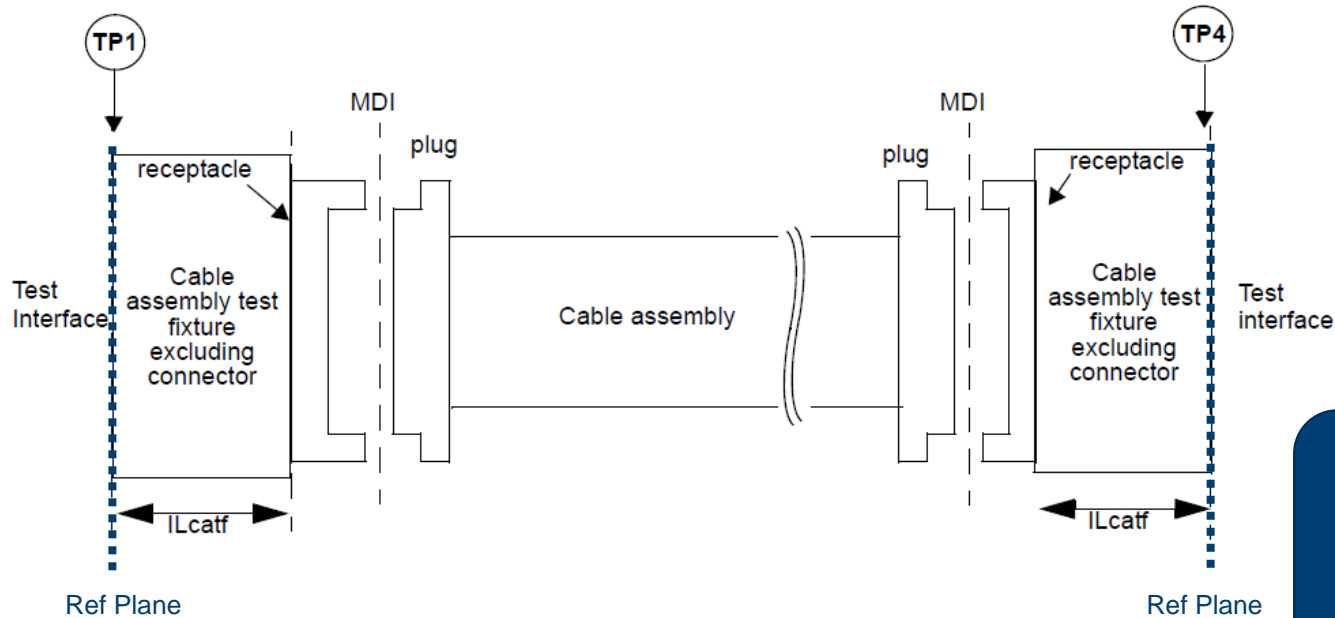
fixtures need to be removed from test results → de-embedding

Source: PCI-SIG Electrical Work Group (EWG): PCIe 5.0/6.0 External Cable Specification (in progress)



REFERENCE PLANE DEFINITION IN IEEE 802.3

EXAMPLE: 802.3ck COPPER CABLE ASSEMBLIES (CR)

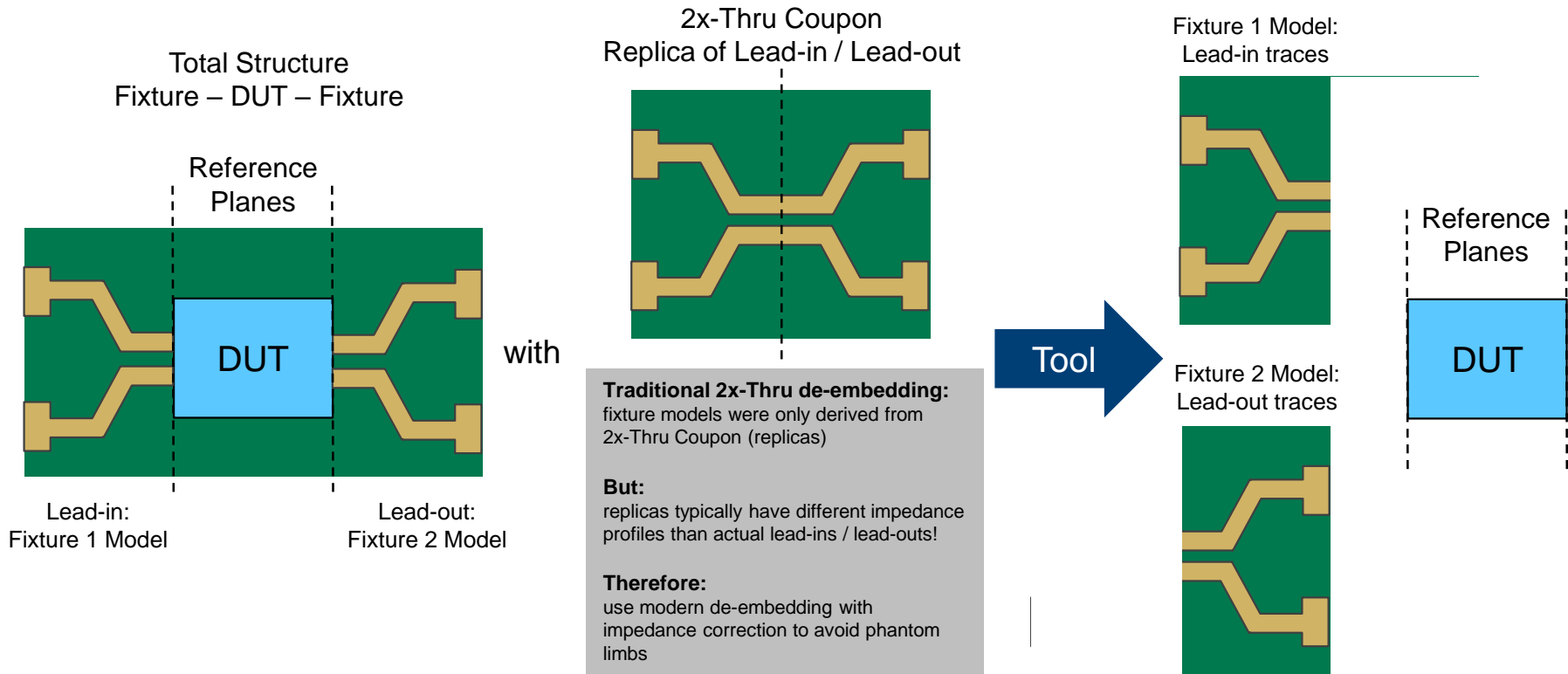


fixture are included
in test results
→ no de-embedding

Source: IEEE Std 802.3bj-2014

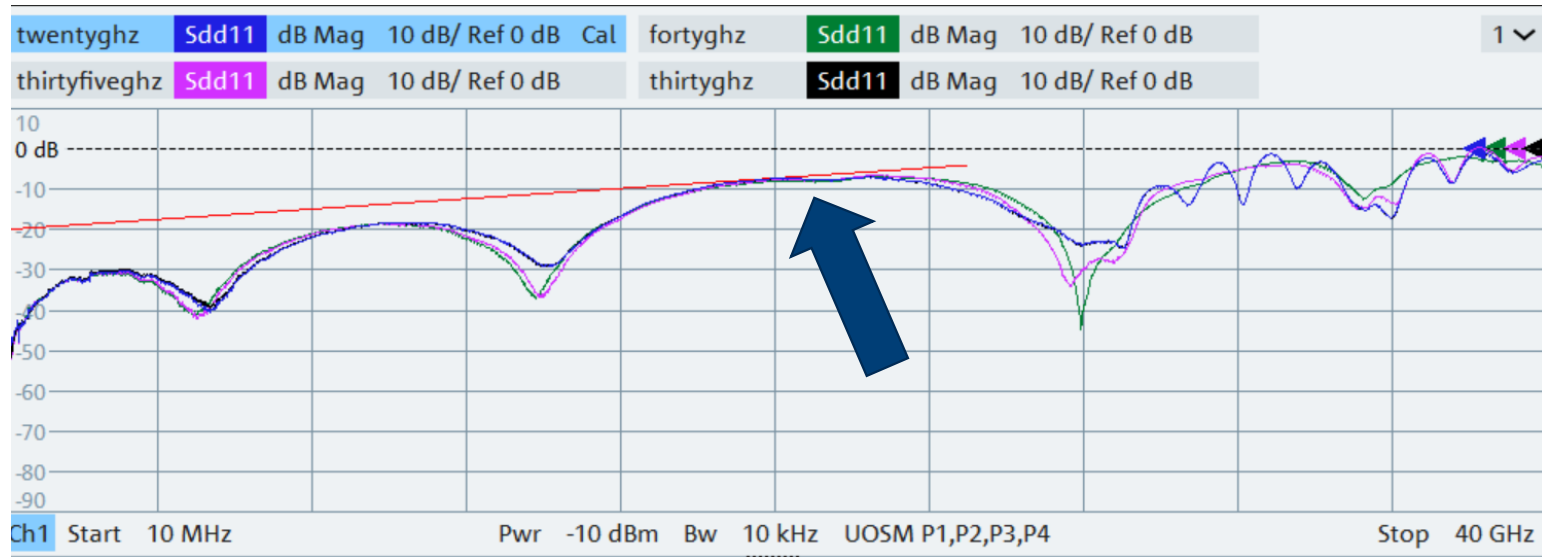


TEST FIXTURE CHARACTERIZATION AND DE-EMBEDDING HOW IT WORKS



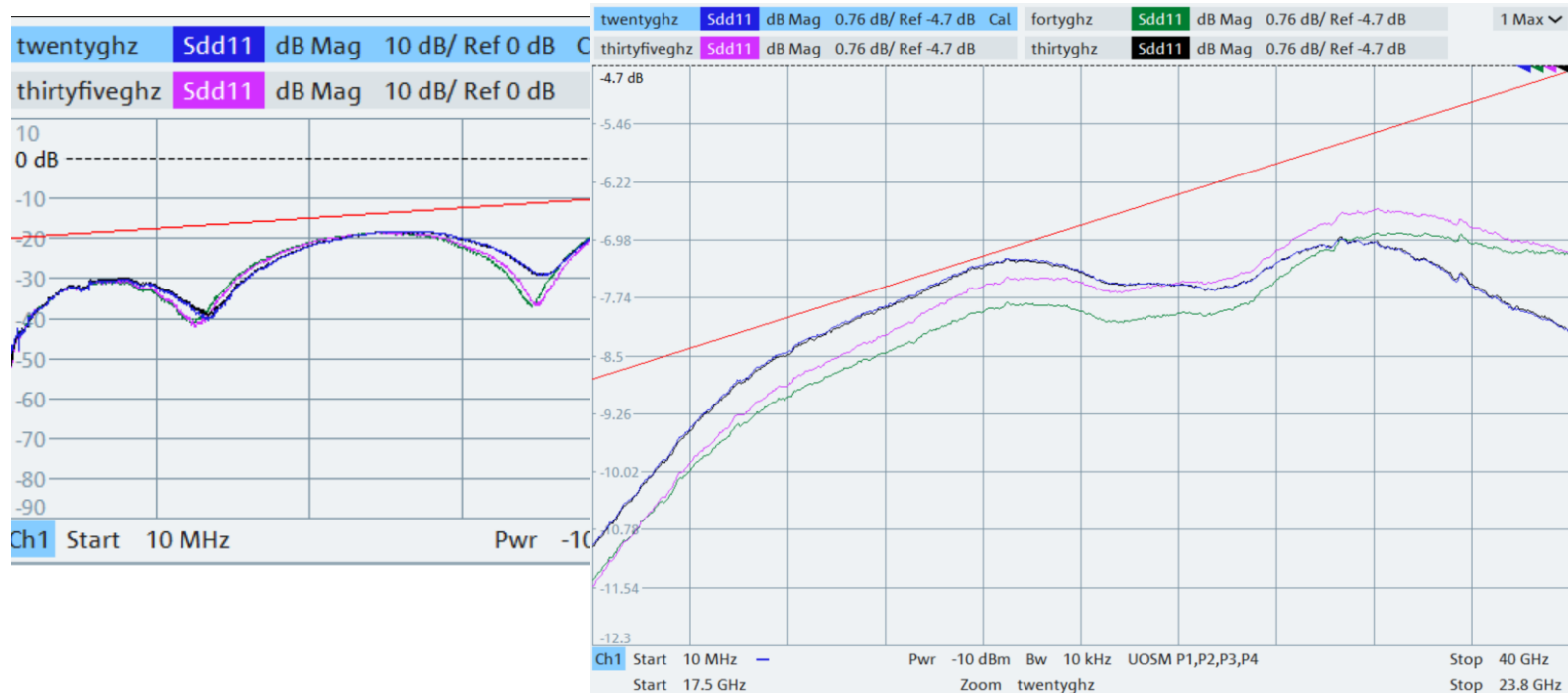
TEST FIXTURE CHARACTERIZATION AND DE-EMBEDDING EXAMPLE: PCIe 5.0 CEM CONNECTOR FIXTURE

For best results: characterize fixture lead-ins / lead-outs up to 40 GHz



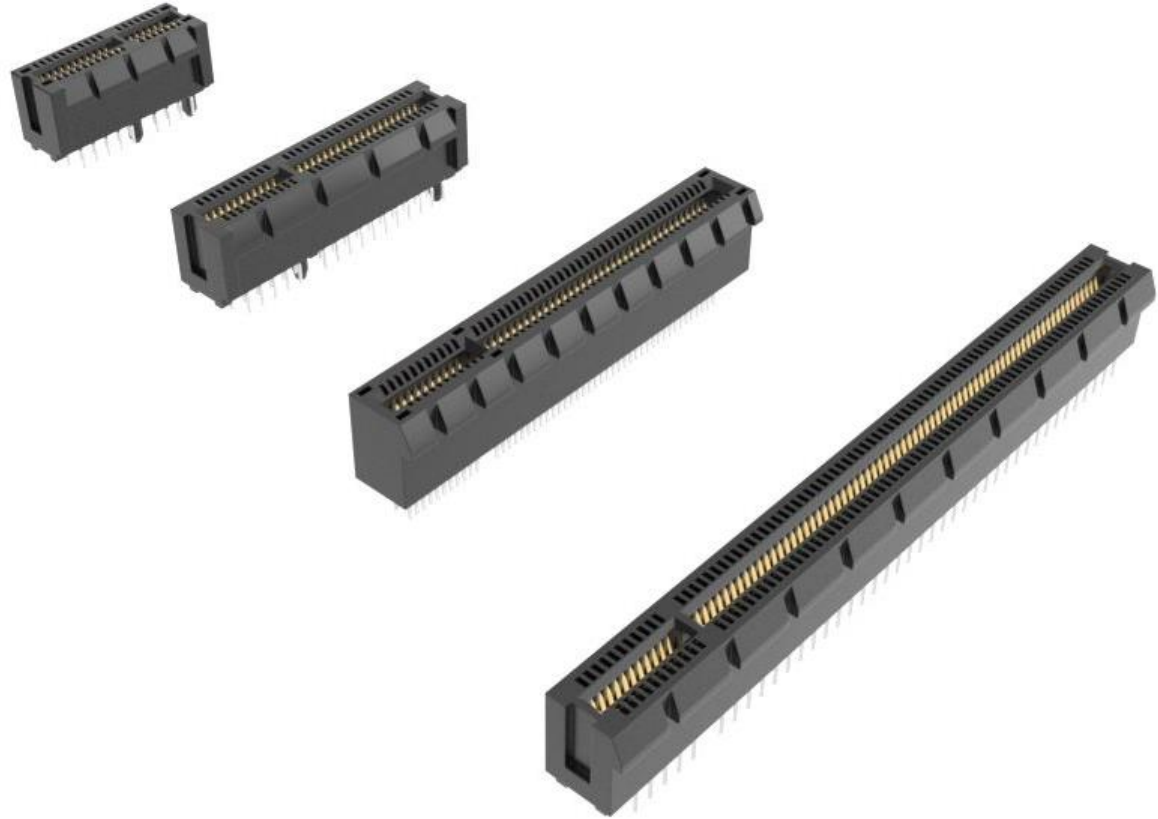
TEST FIXTURE CHARACTERIZATION AND DE-EMBEDDING EXAMPLE: PCIE 5.0 CEM CONNECTOR FIXTURE

For best results: characterize fixture lead-ins / lead-outs up to 40 GHz



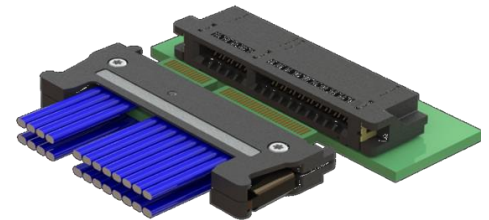
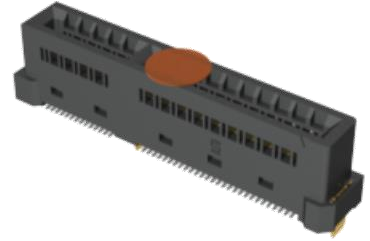
**HIGH-SPEED
CABLES FOR
PCIe 5.0 / 6.0 AND
IEEE802.3ck**

**REQUIREMENTS
AND
IMPLEMENTATIONS**

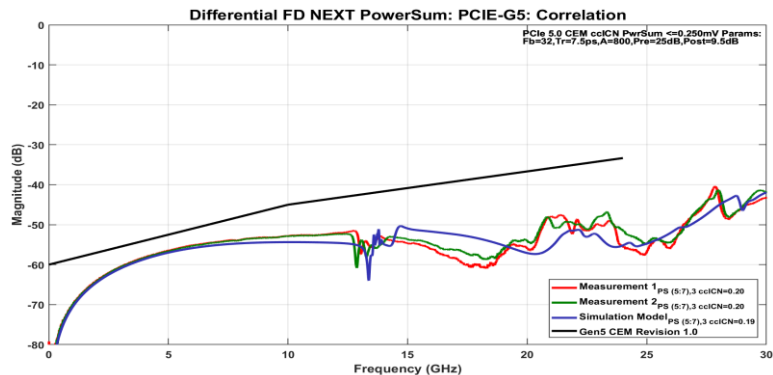
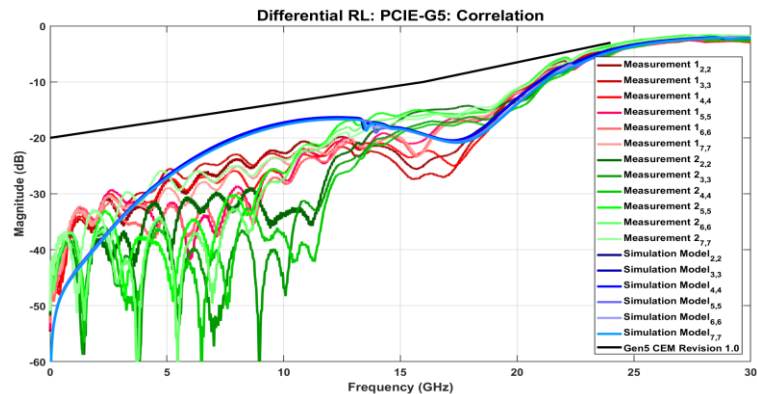
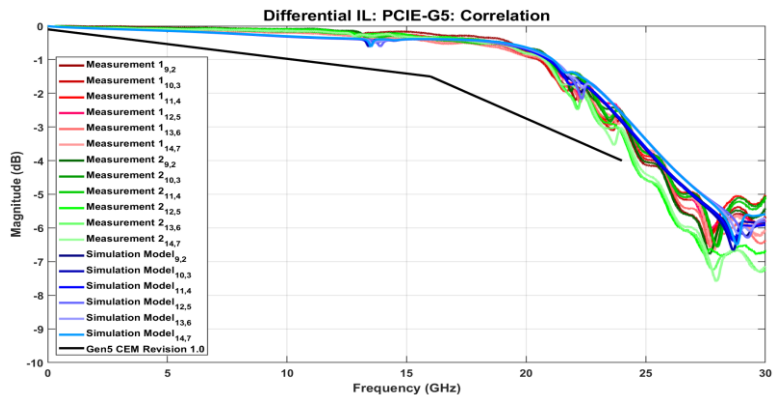


PCIe CONNECTOR AND CABLE PERFORMANCE: MAIN REQUIREMENTS

- ▶ PCIe 5.0 and 6.0 CEM Connector
 - FD IL, RL and Crosstalk limits
 - Excursions for crosstalk introduced with PCIe 5.0: cclCN (expected to be continued in PCIe 6.0)
 - Excursions for return loss expected to be introduced with PCIe 6.0: iRL (not released)
- ▶ PCIe 5.0 and 6.0 Cable Standard around SFF-TA-1016 (internal cables) and SFF-TA-1032 (external cables) is expected but not released
 - Separate requirements for mated cable assemblies and mated cable connectors
 - FD IL, RL and Crosstalk limits
 - Excursions for crosstalk (cclCN) and return loss (iRL)
 - Intra-Pair Skew



PCIe 5.0 FREQUENCY DOMAIN REQUIREMENTS: EXAMPLES



PCIe CEM 5.0 frequency limits and example measurements



TEST PARAMETERS IN PCIe 5.0 / 6.0

EXAMPLE: PCIe 5.0 / 6.0 INTERNAL AND EXTERNAL CABLES

Why excursions: introduction of iRL and cclCN

- ▶ connectors and cables may slightly exceed a frequency domain specification limit line
- ▶ slight excursions do not necessarily cause system failures as proven by simulation
- ▶ introduction of excursion metrics:
 - for return loss: iRL (integrated Return Loss)
expected (unreleased specifications)
 - for crosstalk: cclCN (component contribution to Integrated Crosstalk Noise)
expected (unreleased specifications)
already introduced for PCIe 5.0 CEM (released)

what excursions are more critical, what are less critical?
→ weighting according to power spectrum of PCIe signal

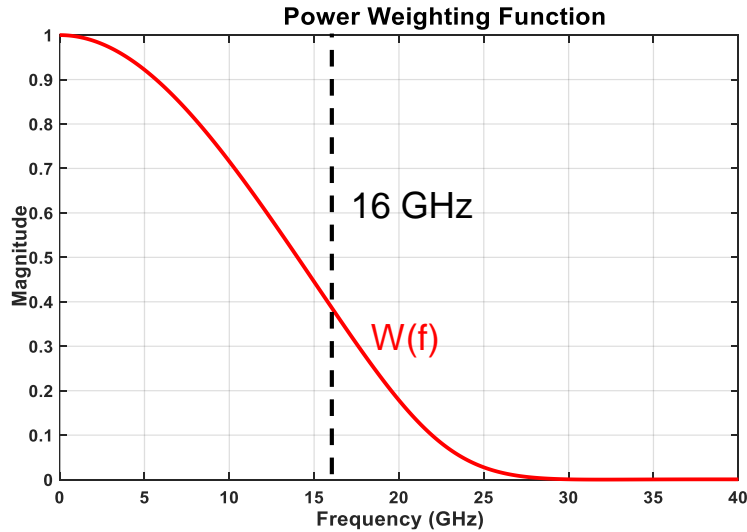
TEST PARAMETERS IN PCIe 5.0 / 6.0

EXAMPLE: PCIe 5.0 / 6.0 INTERNAL AND EXTERNAL CABLES

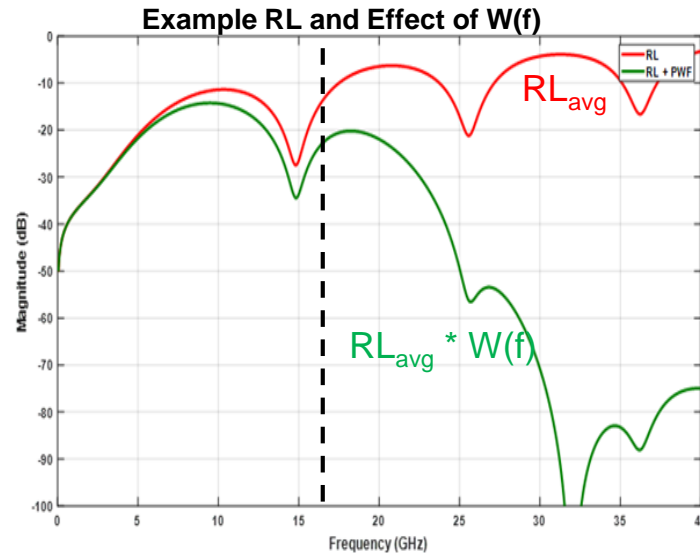
iRL (integrated Return Loss)

- ▶ Integration of averaged return loss after a power weighting filter $W(f)$
- ▶ $W(f)$ represents transferred power for 16 GHz Nyquist signaling

$$iRL = dB \left(\sqrt{\frac{1}{N} \sum_{i=1}^N W(f_i) RL_{avg}^2(f_i)} \right)$$



$$W(f_i) = \text{sinc}^2(f_i/f_b) \left(\frac{1}{(1 + (f_i/f_t)^4)} \right) \left(\frac{1}{(1 + (f_i/f_r)^8)} \right)$$



$$RL_{avg}(f_i) = (|RL_{11}(f_i)| + |RL_{22}(f_i)|) / 2$$



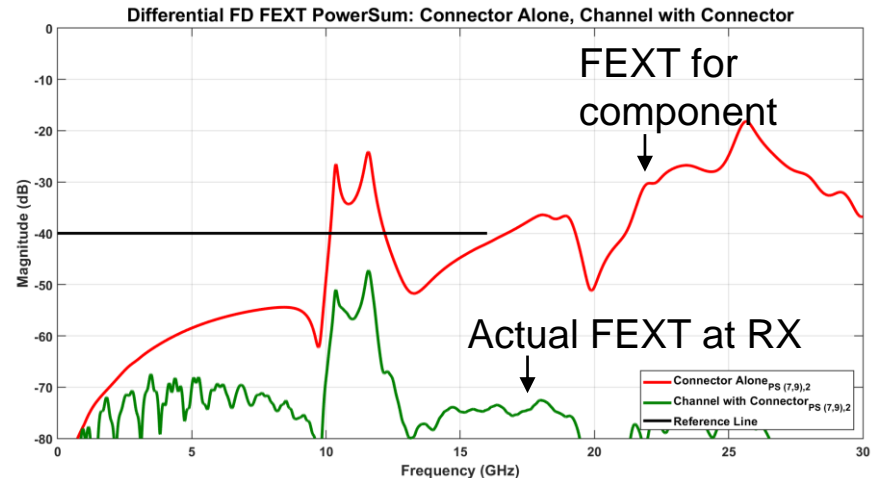
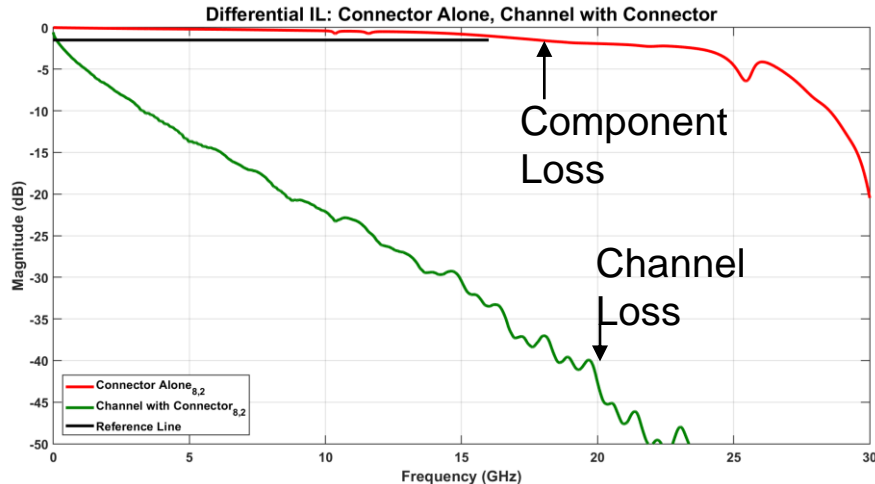
TEST PARAMETERS IN PCIe 5.0 / 6.0

EXAMPLE: PCIe 5.0 / 6.0 INTERNAL AND EXTERNAL CABLES

ccICN (component contribution to Integrated Crosstalk Noise)

- ▶ Similar to IRL, but also filters response by reference channel loss
 - FEXT and NEXT have different loss coefficients
 - FEXT is attenuated by end to end channel loss.
 - NEXT is much shorter (less attenuated)

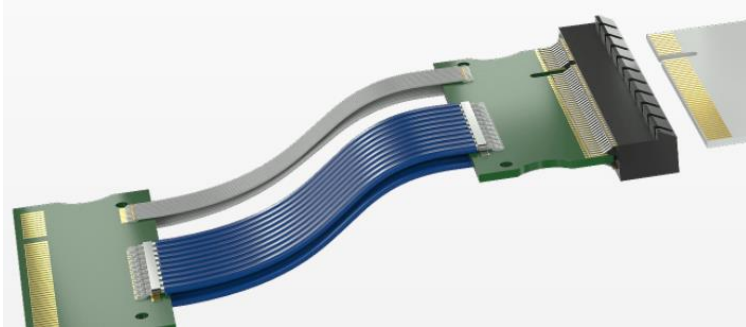
$$\sigma_{ICN} = \sqrt{2 \cdot \Delta f \cdot \sum_{f_{min}}^{f_{max}} \frac{A^2}{f_b} \cdot PWF(f) \cdot 10^{\left(\frac{PwrSumXt}{10}\right)} \cdot 10^{\left(\frac{-2 \cdot Kx_a \cdot f}{10}\right)}}$$



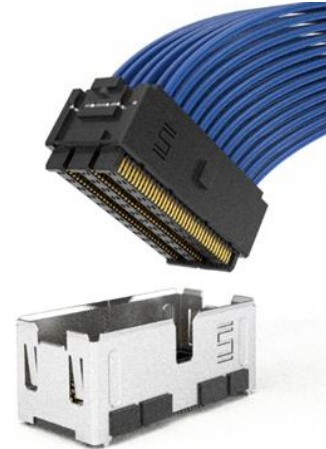
NON-STANDARD CONNECTORS AND CABLES

- ▶ SI requirements for CEM, SFF-TA-1016 and SFF-TA-1032 form factors may not apply to other form factors, such as:

CEM Extender Cables expect to have worse performance than e.g. the smaller SFF-TA-1016



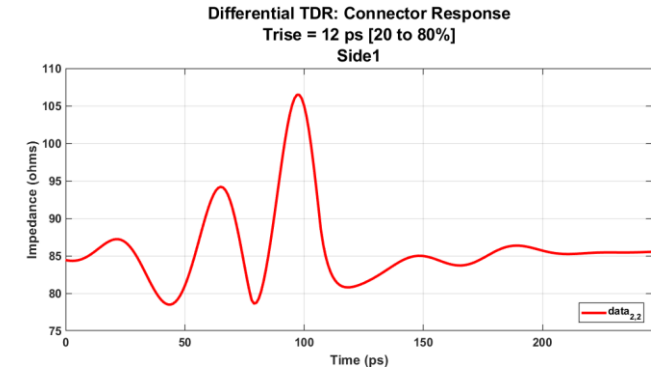
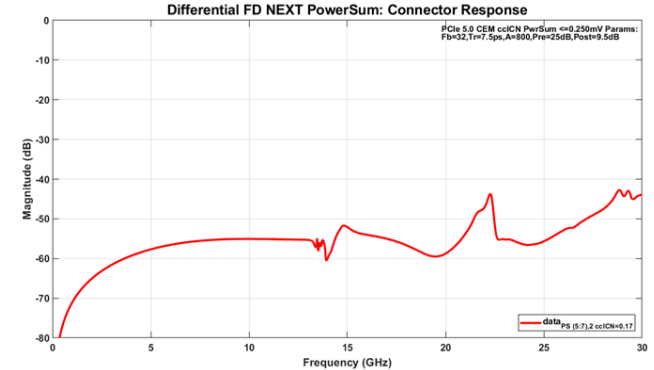
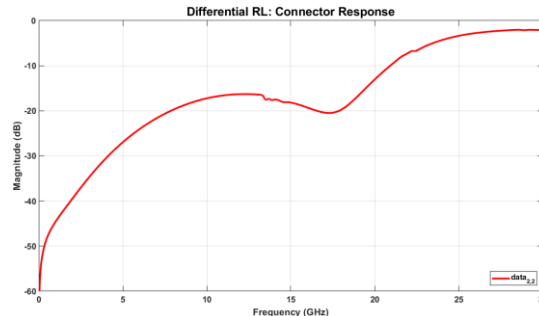
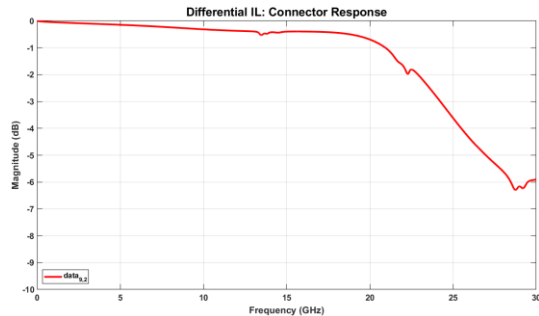
Array Connectors\Cables are more dense and can expect more crosstalk than SFF-TA-1016



So, what can we do?

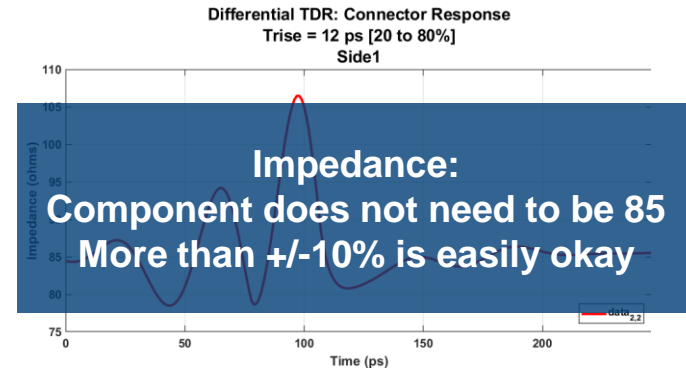
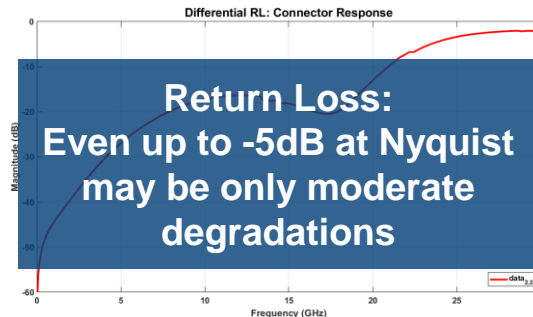
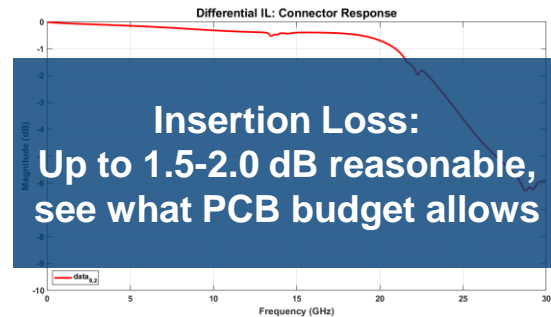
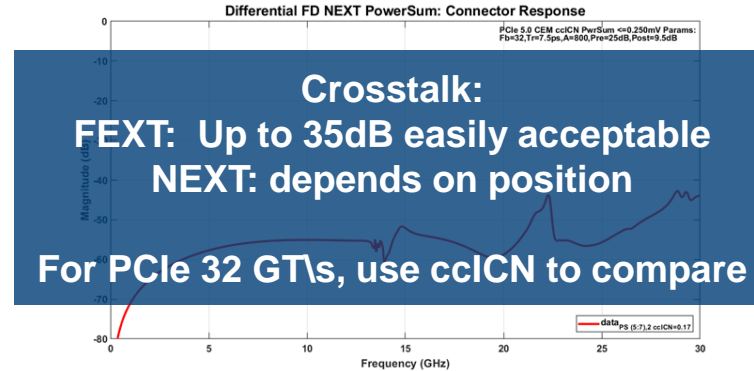
STEP 1: FREQUENCY DOMAIN CONSIDERATION

- ▶ Other form factors are taller:
having more loss and lower resonances,
with more pins and noise
- ▶ Anecdotal recommendations:
 - “Rule of Thumb”



STEP 1: FREQUENCY DOMAIN CONSIDERATION

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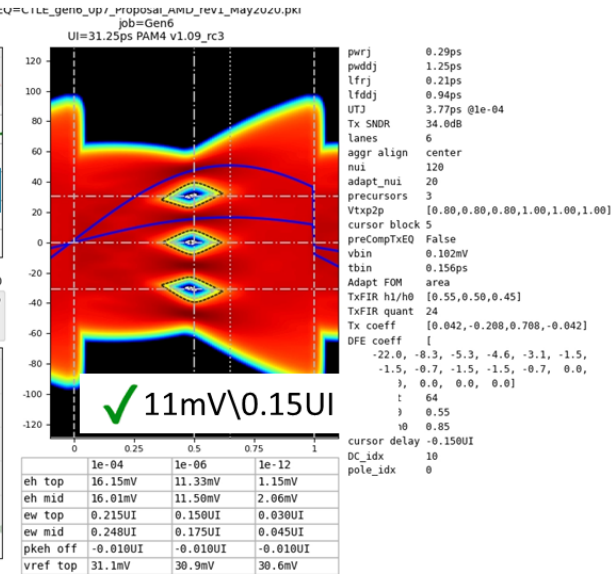
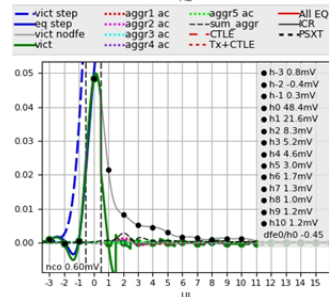
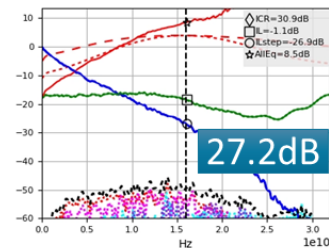
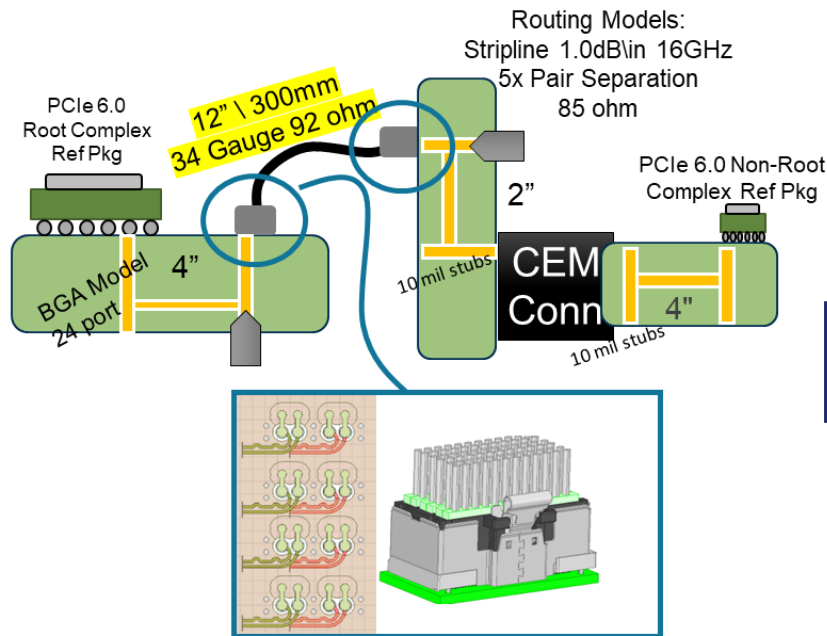


STEP 2: CHANNEL SIMULATION

EXAMPLE PCIe 6.0 CABLED TOPOLOGY

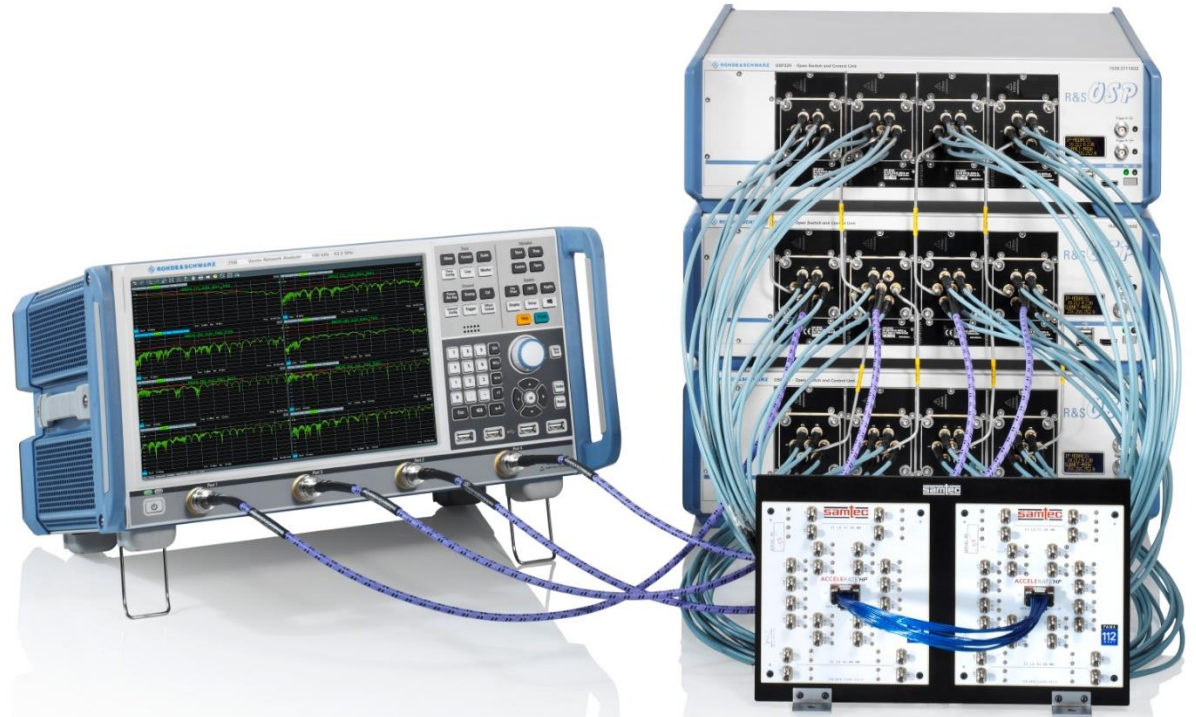
► Why simulation?

- Non-Interoperable captive systems, impedances other than 85, specific application models



HIGH-SPEED CABLES FOR PCIe 5.0 / 6.0 AND IEEE802.3ck

TEST SOLUTIONS: FIXTURE REMOVAL, TEST AUTOMATION

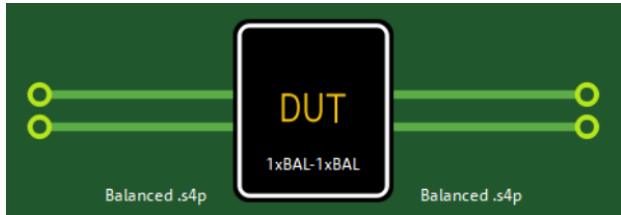


TEST FIXTURE CHARACTERIZATION

R&S DE-EMBEDDING ASSISTANT

Step 1: Topology

- DUT
- Lead-in
- Lead-out

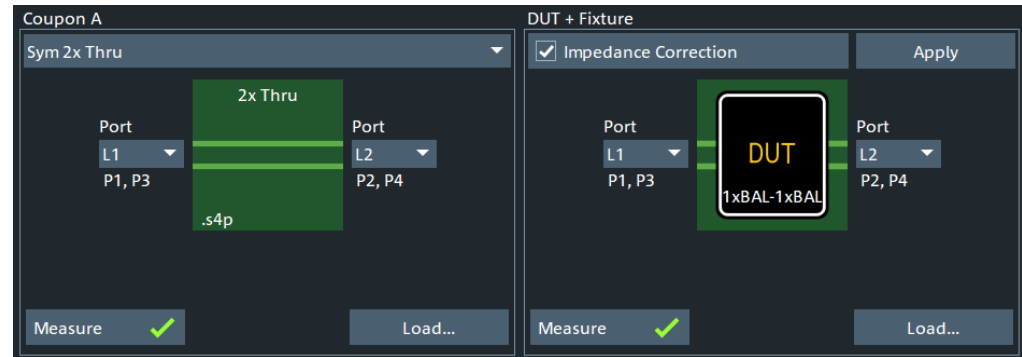


Step 2: Measure/Load

- Coupon(s)
- Total structure

Step 3: Result

- Apply



► Industry accepted modeling algorithms

- K210 EZD: Easy De-embedding
- K220 ISD: In-Situ De-embedding
- K230 SFD: Smart Fixture De-embedding

Method	Offset	TRL	Fixture Model De-embed
Correction (kit)	Easy	Complex	Easy
Speed	Fast	Slow	Fast
Accuracy	Poor	Moderate	Best



TEST OF SAMTEC SI-FLY FLYOVER EVALUATION KIT

RETURN LOSS, INSERTION LOSS, AND TDR COMPARISON



VERIFICATION OF PCIe 5.0, 6.0 CABLES AND CONNECTORS WITH VECTOR NETWORK ANALYZER

► Required measurements:

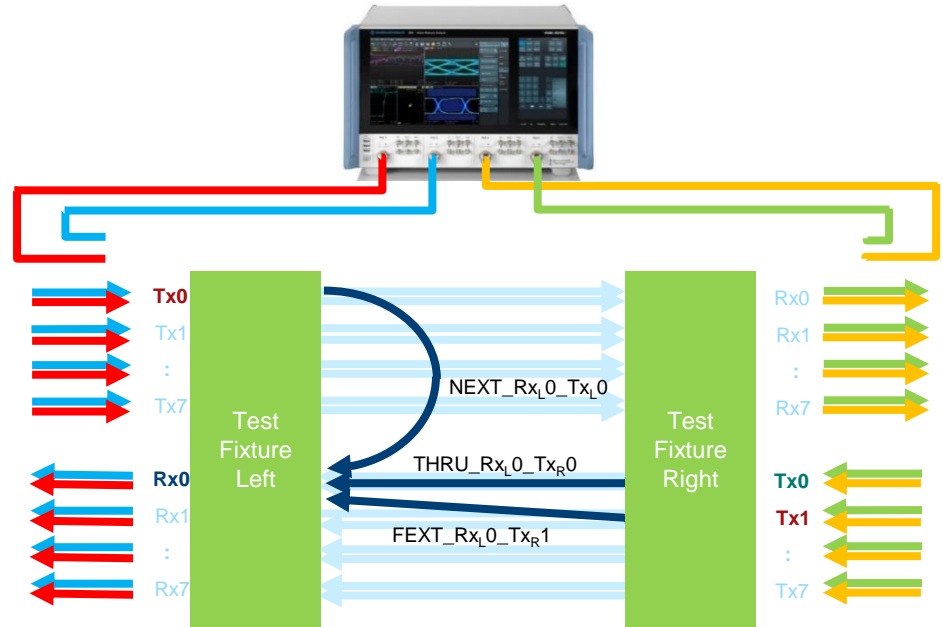
- Insertion loss S_{dd21}
- Return loss S_{dd11} and S_{dd22}
- Near-end crosstalk (NEXT)
- Far-end crosstalk (FEXT)

► Testing with 4 port VNA

- multiple 4-port measurements

► Postprocessing:

- Integrated return loss iRL
- Power sum MDNEXT and $cICN_{NEXT}$
- Power sum MDFEXT and $cICN_{FEXT}$
- Intra-pair skew: EIPS
- Inter-pair skew (lane-to-lane)



Example PCIe x8 cable

HIGH SPEED INTERFACE TESTING SOLUTION



32-port (4 lanes)

64-port (8 lanes)

ZNrun Option	ZNrun-K410	ZNrun-K411	ZNrun-K440
DUT example	SFP28 QSFP28 SFP56 QSFP56	SFP112 QSFP112 QSFP-DD112 OSFP	GenZ MCIO Riser CEM CDFP
Technology	IEEE802.3bj/by/cd	IEEE802.3ck	PCIe 5.0/6.0
Recommended VNA Frequency	26.5 GHz	50 GHz	43.5 GHz
Fixture de-embedding	Optional	Optional	Mandatory
SI test items	ERL COM	ERL COM	iRL cclCN EIPS



AUTOMATED VERIFICATION WITH VNA AND MULTIPOINT SWITCH MATRIX



Setup Calibrate Measure

- ▶ Solution: R&S ZNrun cable test client, VNA, and OSP
 - Predefined topology for multi-lane setup
 - Test plan of PCIe and IEEE802.3
 - Flexible de-embedding
 - Test cases selection
 - Efficient calibration
 - Report generation
 - Data export
 - Automation interfaces

DE-/EMBEDDING			
Port	Usage	Touchstone File	Interchange Mode
Fixture left	Deembedding		Standard
Fixture right	Deembedding		Standard

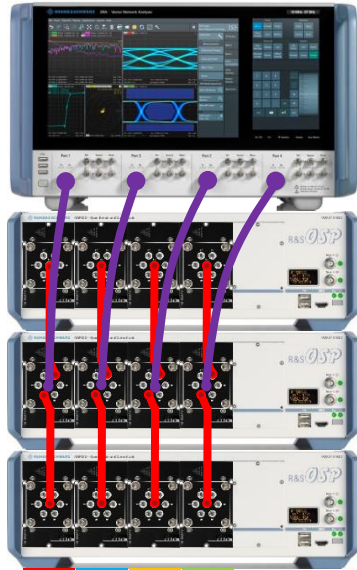
Test Case Selection							
RX Lane	Y	Test Case	Y	Execute	Y	TX Lanes	Y
0		THRU / SKEW / TDR		<input checked="" type="checkbox"/>		0	
		NEXT		<input checked="" type="checkbox"/>		0,1,2	
		FEXT		<input checked="" type="checkbox"/>		1,2	
1		THRU / SKEW / TDR		<input checked="" type="checkbox"/>		1	
		NEXT		<input checked="" type="checkbox"/>		0,1,2	
		FEXT		<input checked="" type="checkbox"/>		0,2	
2		THRU / SKEW / TDR		<input checked="" type="checkbox"/>		2	
		NEXT		<input checked="" type="checkbox"/>		0,1,2	
		FEXT		<input checked="" type="checkbox"/>		0,1	
		Calculate psNEXT (L)		<input checked="" type="checkbox"/>			
		Calculate psNEXT (R)		<input checked="" type="checkbox"/>			
		Calculate psFEXT (L)		<input checked="" type="checkbox"/>			



VERIFICATION OF PCIe 5.0 / 6.0 CABLES AND CONNECTORS: GENERAL CONSIDERATIONS

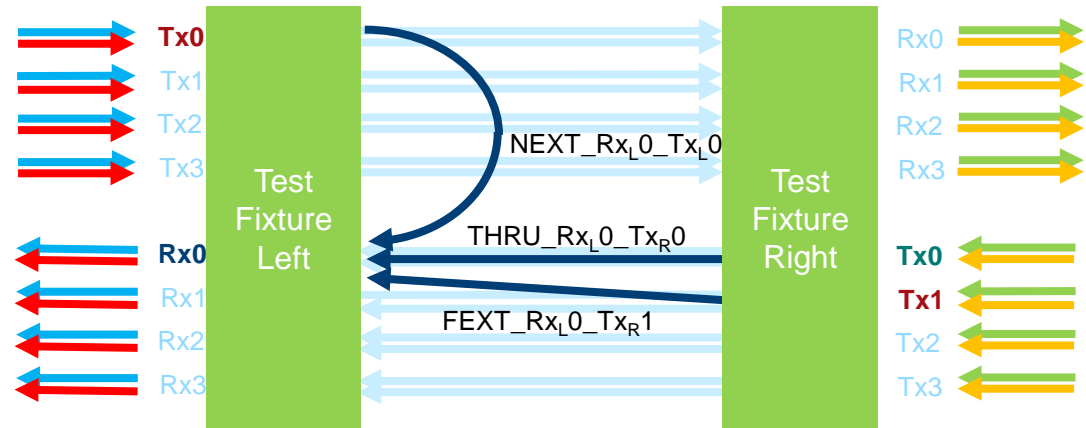
Measurements:

automation with switch matrix:
example for PCIe x8



total = 64 ports

	PCIe x4	PCIe x8	PCIe x16
number of lanes (Tx + Rx)	4 Tx + 4 Rx	8 Tx + 8 Rx	16 Tx + 16 Rx
number of ports for full testing (all lanes and all crosstalk combinations)	32	64	128
number of 4-port measurements for full testing (all lanes and all crosstalk combinations)	8 x THRU 4 x 4 = 16 x NEXT_L 4 x 4 = 16 x NEXT_R 3 x 4 = 12 x FEXT_L 3 x 4 = 12 x FEXT_R total: 64 4-port meas.	16 x THRU 8 x 8 = 64 x NEXT_L 8 x 8 = 64 x NEXT_R 7 x 8 = 56 x FEXT_L 7 x 8 = 56 x FEXT_R total: 256 4-port meas.	32 x THRU 16 x 16 = 256 x NEXT_L 16 x 16 = 256 x NEXT_R 15 x 16 = 240 x FEXT_L 15 x 16 = 240 x FEXT_R total: 1024 4-port meas.

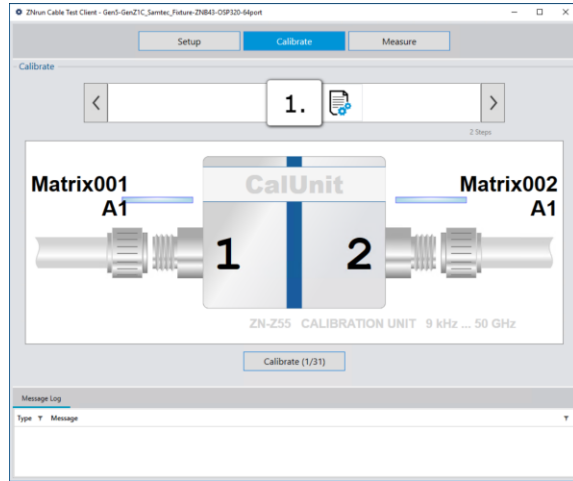



VERIFICATION OF PCIe 5.0 / 6.0 CABLES AND CONNECTORS: GENERAL CONSIDERATIONS

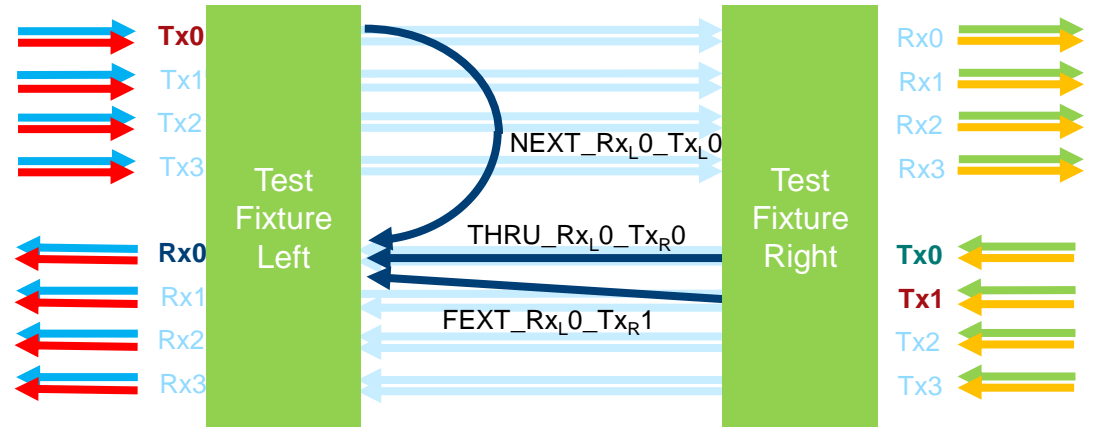
Calibration:

automation of calibration

example for PCIe x4 w. R&S ZNrun

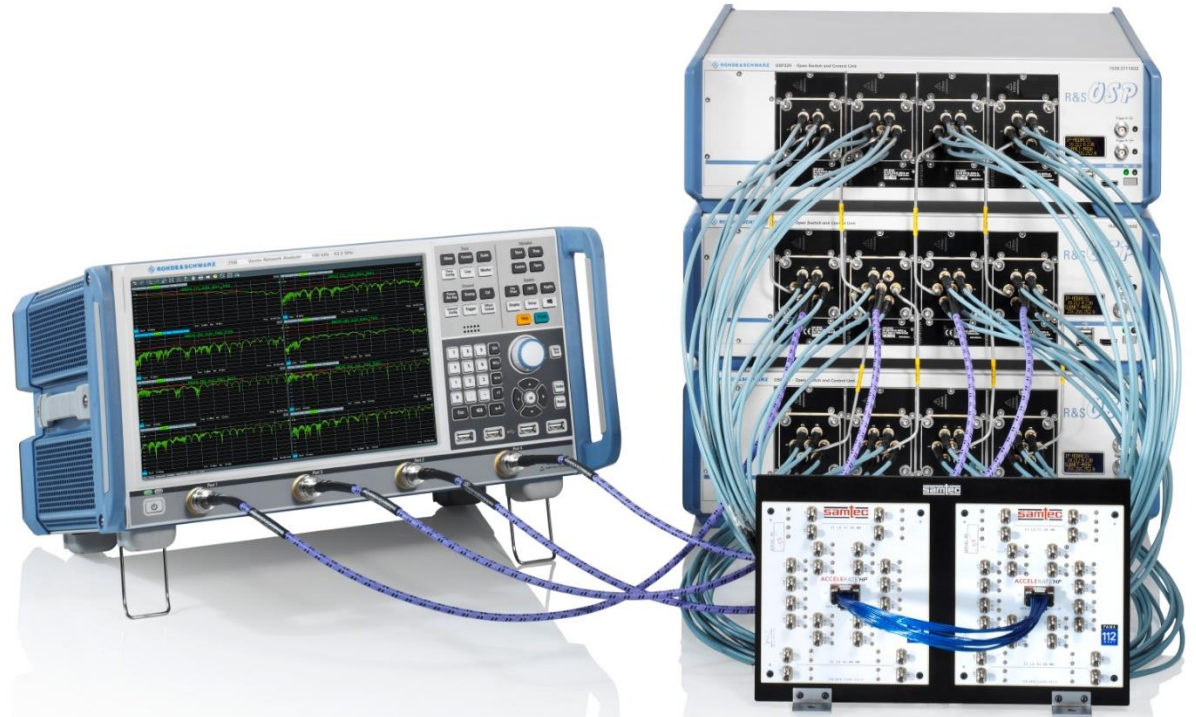


	PCIe x4	PCIe x8	PCIe x16
number of lanes (Tx + Rx)	4 Tx + 4 Rx	8 Tx + 8 Rx	16 Tx + 16 Rx
number of ports for full testing (all lanes and all crosstalk combinations)	32	64	128
number of 4-port measurements for full testing (all lanes and all crosstalk combinations)	64 4-port groups:	256 4-port groups:	1024 4-port groups:
standard calibration (3 connections per 4-port)	64 x 3 = 192	256 x 3 = 768	1024 x 3 = 3072
optimized calibration 	31	63	127



HIGH-SPEED CABLES FOR PCIe 5.0 / 6.0 AND IEEE802.3ck

PRACTICAL DEMO



Find out more

www.rohde-schwarz.com

www.samtec.com

Thank you!

ROHDE & SCHWARZ

Make ideas real

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